Enhanced compositional sensitivity in atomic force microscopy by the excitation of the first two flexural modes$^1$ RICARDO GARCIA, NICOLAS F. MARTINEZ, SHIVPRASAD PATIL, JOSE R. LOZANO, Instituto de Microelectronica de Madrid, CSIC — We demonstrate that the compositional sensitivity of an atomic force microscope is enhanced by the simultaneous excitation of its first two normal eigenmodes$^{1-2}$. The coupling of those modes by the non-linear probe-surface interactions enables to map compositional changes in several conjugated molecular materials with a phase shift sensitivity that is about two orders of magnitude higher than the one achieved in amplitude modulation atomic force microscopy.


$^1$This work was financially supported by the European Commission (FORCETOOL, NMP4-CT-2004-013684).